



XTMS65R220D

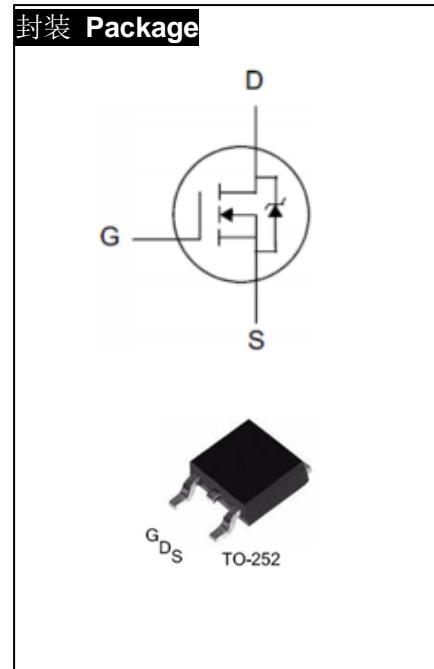
650V N-ch Planar MOSFET

Product Description

BV_{DSS}	650	V
I_D	15	A
$R_{DS(ON),Typ.}$	0.22	Ω

General Features

- New revolutionary high voltage technology
- $R_{DS(ON),typ.}=0.22\Omega @ V_{GS}=10V$
- High peak current capability
- Ultra low Gate Charge
- Periodic avalanche rated



Device	Package	Marking
XTMS65R220D	TO-252	XTMF65R220D

Absolute Maximum Ratings $T_j=25^\circ C$

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-to-Source Voltage	650	V
V_{GSS}	Gate-to-Source Voltage	± 30	
I_D	Continuous Drain Current	15	A
I_{DM}	Pulsed Drain Current at $V_{GS}=10V$	60	
E_{AS}	Single Pulse Avalanche Energy	304	mJ
P_D	Power Dissipation	131	W
	Derating Factor above $25^\circ C$	1.05	W/ $^\circ C$
T_J & T_{STG}	Operating and Storage Temperature Range	-55 to 150	$^\circ C$

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.



Thermal Characteristics

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.95	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	°C/W

Electrical Characteristics $T_j=25^\circ C$

OFF Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
BV_{DSS}	Drain-to-Source Breakdown Voltage	650	-	-	V	$V_{GS}=0V, I_D=250\mu A$
I_{DSS}	Drain-to-Source Leakage Current	-	-	1.0	μA	$V_{DS}=650V, V_{GS}=0V$
I_{GSS}	Gate-to-Source Leakage Current	-	-	+100	nA	$V_{GS}=+30V, V_{DS}=0V$
		-	-	-100		$V_{GS}=-30V, V_{DS}=0V$

ON Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	-	0.22	0.26	Ω	$V_{GS}=10V, I_D=8A$
$V_{GS(TH)}$	Gate Threshold Voltage	3	3.5	4	V	$V_{DS}=V_{GS}, I_D=250\mu A$



Dynamic Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
C_{iss}	Input Capacitance	-	1210	1400	pF	$V_{GS}=0V$, $V_{DS}=50V$, $f=1.0MHz$
C_{rss}	Reverse Transfer Capacitance	-	0.2	-		
C_{oss}	Output Capacitance	-	74	-		
Q_g	Total Gate Charge	-	24.7	-	nC	$V_{DD}=480V$, $I_D=15A$, $V_{GS}=10V$
Q_{gs}	Gate-to-Source Charge	-	8.2	-		
Q_{gd}	Gate-to-Drain (Miller) Charge	-	8.5	-		

Resistive Switching Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
$td_{(ON)}$	Turn-on Delay Time	-	14	-	ns	$V_{DD}=380V$, $I_D=8A$, $V_{GS}=10V$ $R_g=2.3\Omega$
t_{rise}	Rise Time	-	8	-		
$td_{(OFF)}$	Turn-Off Delay Time	-	55	-		
t_{fall}	Fall Time	-	7	-		

Source-Drain Body Diode Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
V_{SD}	Diode Forward Voltage	-	-	1.2	V	$I_S=15A$, $V_{GS}=0V$ $V_{GS}=0V$ $I_S=7.5A$, $di/dt=100A/\mu s$
t_{rr}	Reverse Recovery Time	-	240	-	ns	
Q_{rr}	Reverse Recovery Charge	-	2	-	uC	

[1] Pulse width $\leq 300\mu s$; duty cycle $\leq 2\%$



Typical Characteristics

Figure1. Safe operating area

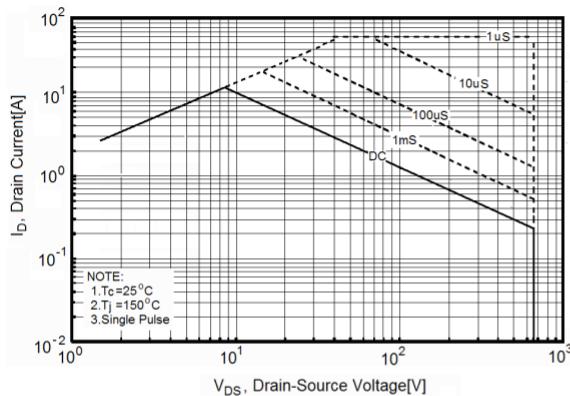


Figure2. Safe operating area for TO-220F

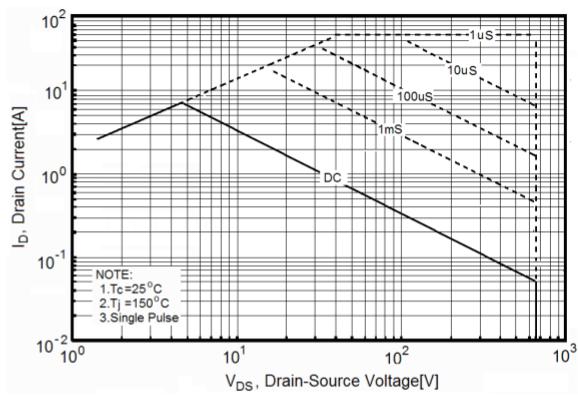


Figure3. Source-Drain Diode Forward Voltage

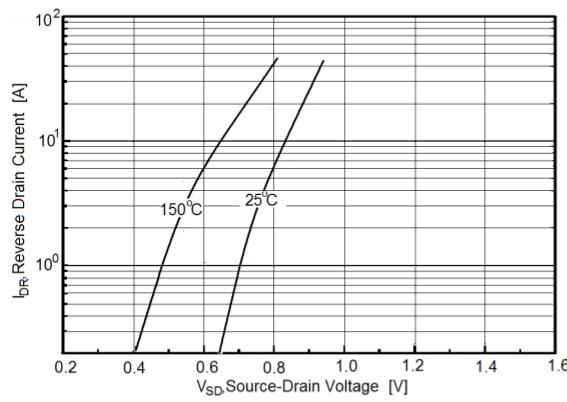


Figure4. Output characteristics

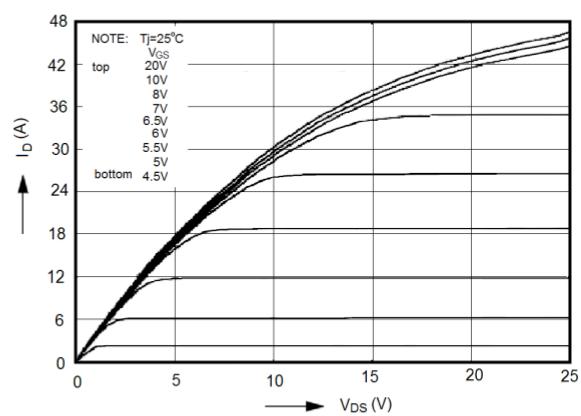


Figure5. Transfer characteristics

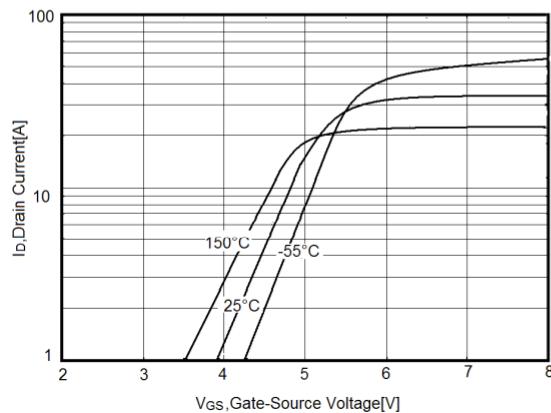
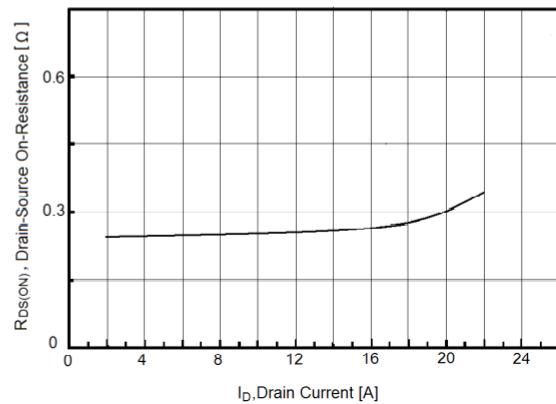


Figure6. Static drain-source on resistance





Typical Characteristics(Cont.)

Figure7. $R_{DS(ON)}$ vs Junction Temperature

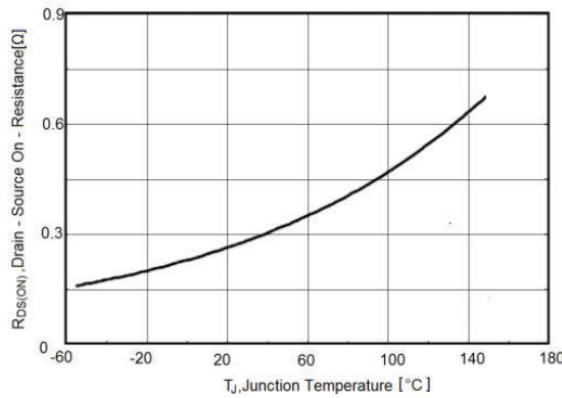


Figure8. BV_{DSS} vs Junction Temperature

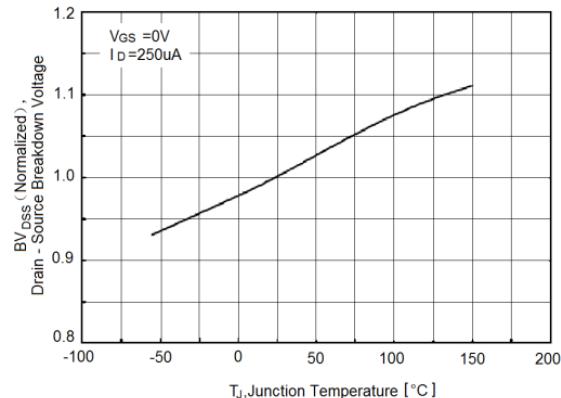


Figure9. Maximum I_D vs Junction Temperature

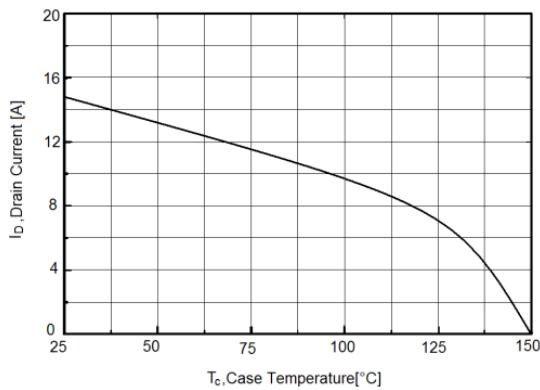


Figure10. Gate charge waveforms

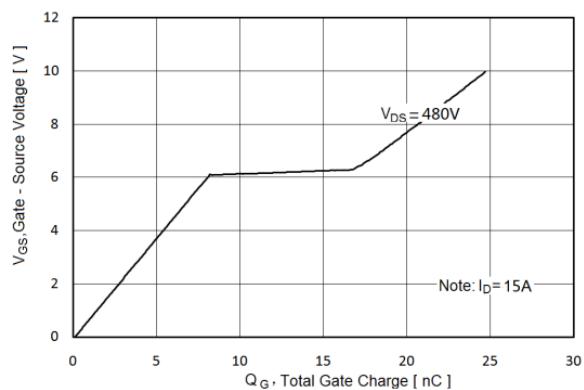


Figure11. Capacitance

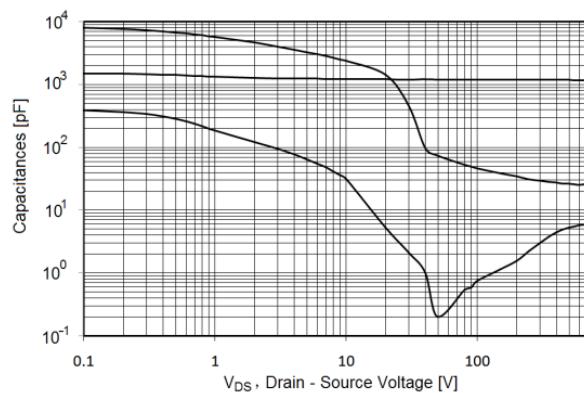
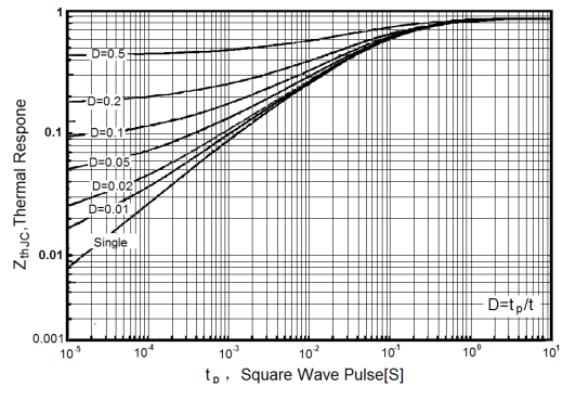


Figure12. Transient Thermal Impedance





Test Circuits and Waveforms

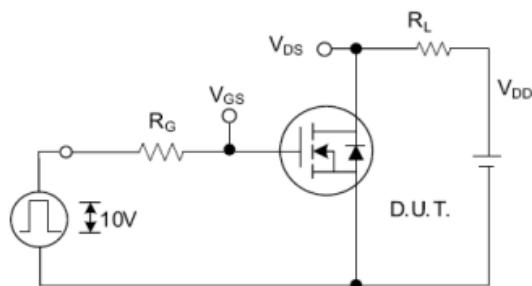


Fig. 2.1 Switching Test Circuit

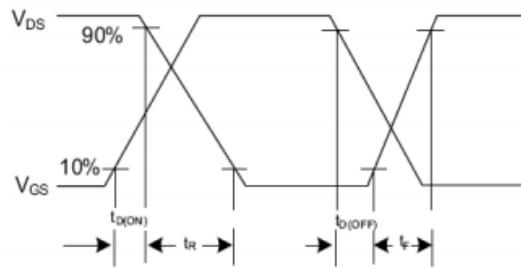


Fig. 2.2 Switching Waveforms

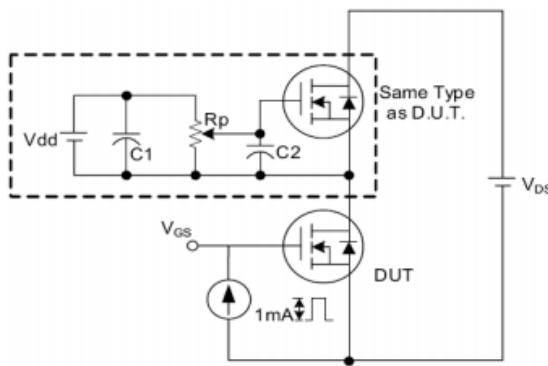


Fig. 3.1 Gate Charge Test Circuit

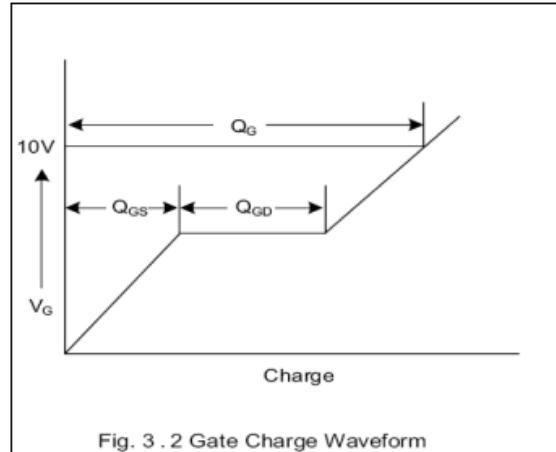


Fig. 3.2 Gate Charge Waveform

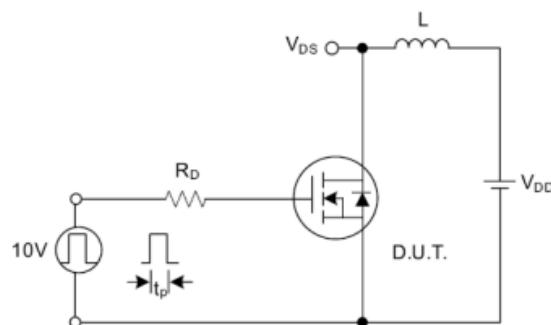


Fig. 4.1 Unclamped Inductive Switching Test Circuit

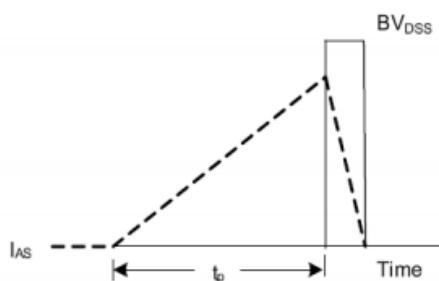


Fig. 4.2 Unclamped Inductive Switching Waveforms